NAME

CUTEST_ceh_threaded - CUTEst tool to evaluate the sparse Lagrangian Hessian matrix in finite element format.

SYNOPSIS

CALL CUTEST_ceh_threaded(status, n, m, X, Y, ne, lhe_ptr, HE_row_ptr, HE_val_ptr, lhe_row, HE_row, lhe_val, HE_val, byrows, thread)

DESCRIPTION

The CUTEST ceh threaded subroutine evaluates the Hessian matrix of the Lagrangian function $l(x, y) = f(x) + y^T c(x)$ for the problem decoded into OUTSDIF.d at the point (x, y) = (X, Y). This Hessian matrix is stored as a sparse matrix in finite element format

$$H = \sum_{e=1}^{ne} H_{e,}$$

 $H = \sum_{e=1}^{ne} H_{e},$ where each square symmetric element H_e involves a small subset of the rows of the Hessian matrix.

The problem under consideration consists in minimizing (or maximizing) an objective function f(x) over all $x \in \mathbb{R}^n$ subject to general equations $c_i(x) = 0$, $(i \in 1, \dots, m_E)$, general inequalities $c_i^i \le c_i(x) \le c_i^{u_i}$ $(i \in 1, \dots, m_E)$ $m_F + 1, \dots, m$), and simple bounds $x^l \le x \le x^u$. The objective function is group-partially separable and all constraint functions are partially separable.

ARGUMENTS

The arguments of CUTEST_ceh_threaded are as follows

status [out] - integer

the outputr status: 0 for a successful call, 1 for an array allocation/deallocation error, 2 for an array bound error, 3 for an evaluation error, 4 for an out-of-range thread,

n [in] - integer

the number of variables for the problem,

m [in] - integer

the total number of general constraints,

X [in] - real/double precision

an array which gives the current estimate of the solution of the problem,

Y [in] - real/double precision

an array which gives the Lagrange multipliers,

ne [out] - integer

the number, ne, of "finite-elements" used,

lhe_ptr [in] - integer

the actual declared dimensions of HE_row_ptr and HE_val_ptr,

HE row ptr [out] - integer

HE row ptr(i) points to the position in HE row of the first row index involved with element number e: the row indices of element number e are stored in HE_row between the indices HE_row_ptr(e) and HE_row_ptr(e+1)-1. HE_row_ptr(ne+1) points to the first empty location in HE_row,

HE val ptr [out] - integer

HE val ptr(i) points to the position in HE val of the first nonzero involved with element number i: the values involved in element number e are stored in HE_val between the indices HE_val_ptr(e) and HE_val_ptr(e+1)-1. HE_val_ptr(ne+1) points to the first empty location in HE_val,

lhe_row [in] - integer

the actual declared dimension of HE_row,

HE_row [out] - integer

an array which holds a list of the row indices involved which each element. Those for element e directly preced those for element e+1, e = 1, ..., ne-1. Since the elements are symmetric, HE_row is also the list of column indices involved with each element.

lhe_val [in] - integer

the actual declared dimension of HE_val,

HE_val [out] - real/double precision

an array of the nonzeros in the upper triangle of H_e , evaluated at X and stored by rows, or by columns. Those for element e directly proceed those for element, e+1, i=1, ..., ne-1. Element number e contains the values stored between

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HE_val( HE_val_ptr(e) ) and HE_val( HE_val_ptr(e+1)-1 )
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and involves the rows/columns stored between

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HE_row( HE_row_ptr(e) ) and HE_row( HE_row_ptr(e+1)-1 ).
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byrows [in] - logical

must be set to .TRUE. if the upper triangle of each H_e is to be stored by rows, and to .FALSE. if it is to be stored by columns,

thread [in] - integer

thread chosen for the evaluation; threads are numbered from 1 to the value threads set when calling CUTEST_csetup_threaded.

AUTHORS

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SEE ALSO

CUTEst: a Constrained and Unconstrained Testing Environment with safe threads,

N.I.M. Gould, D. Orban and Ph.L. Toint,

Computational Optimization and Applications 60:3, pp.545-557, 2014.

CUTEr (and SifDec): A Constrained and Unconstrained Testing Environment, revisited,

N.I.M. Gould, D. Orban and Ph.L. Toint,

ACM TOMS, 29:4, pp.373-394, 2003.

CUTE: Constrained and Unconstrained Testing Environment,

I. Bongartz, A.R. Conn, N.I.M. Gould and Ph.L. Toint,

ACM TOMS, 21:1, pp.123-160, 1995.

 $cutest_ueh_threaded(3M),\,sifdecoder(1).$